## Notice of References Cited Application/Control No. 10/599,936 Examiner DAVID M. SINCLAIR Applicant(s)/Patent Under Reexamination OWEN ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0131934	07-2004	Sugnaux et al.	429/209
*	В	US-5,963,417	10-1999	Anderson et al.	361/503
*	C	US-2004/0202934	10-2004	Zaghib et al.	429/231.1
*	D	US-4,422,917	12-1983	Hayfield, Peter C. S.	204/196.01
*	Е	US-6,379,843	04-2002	Yamasaki et al.	429/231.5
*	F	US-6,500,575	12-2002	Shiue et al.	429/405
*	G	US-7,368,202	05-2008	Kurihara et al.	429/209
*	Η	US-2005/0058907	03-2005	Kurihara et al.	429/232
*	I	US-2004/0016646	01-2004	Stucky et al.	205/111
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν	RU 2170467 C1	07-2001	Russian Federat	BEKESH V V et al.	
	0					
	Ρ					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.